

Notice of References Cited	Application/Control No. 10/705,225	Applicant(s)/Patent Under Reexamination FINK ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,025,789	03-1962	HUEBNER WILLIAM C	101/147
*	B	US-3,215,616	11-1965	SPIELMAN WARREN L	422/186.07
*	C	US-4,612,077	09-1986	Tracy et al.	156/345.34
*	D	US-4,941,344	07-1990	Beech et al.	72/456
*	E	US-5,606,911	03-1997	Cane, Paul	101/127
*	F	US-5,728,223	03-1998	Murakami et al.	118/715
*	G	US-5,746,875	05-1998	Maydan et al.	156/345.34
*	H	US-5,851,294	12-1998	Young et al.	118/715
*	I	US-5,935,337	08-1999	Takeuchi et al.	118/724
*	J	US-5,962,085	10-1999	Hayashi et al.	427/585
*	K	US-6,024,799	02-2000	Chen et al.	118/715
*	L	US-6,041,733	03-2000	Kim et al.	118/723E
*	M	US-6,093,086	07-2000	Easter et al.	451/41

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,155,524	12-2000	Legler et al.	248/221.11
*	B	US-6,565,661 B1	05-2003	Nguyen, Tue	118/715
*	C	US-6,641,673 B2	11-2003	Yang, Barry Lee-Mean	118/715
*	D	US-6,758,941 B1	07-2004	Ookawa et al.	156/345.47
*	E	US-6,786,175 B2	09-2004	Dhindsa et al.	118/723E
*	F	US-6,926,803 B2	08-2005	Antolik, Jerrel K.	118/500
*	G	US-6,936,135 B2	08-2005	Antolik, Jerrel K.	118/500
*	H	US-6,942,753 B2	09-2005	Choi et al.	156/345.34
*	I	US-2001/0003271 A1	06-2001	Otsuki, Hayashi	118/723.00I
*	J	US-2003/0037880 A1	02-2003	Carducci et al.	156/345.43
*	K	US-2003/0192645 A1	10-2003	Liu et al.	156/345.33
*	L	US-2004/0060661 A1	04-2004	Nishimoto et al.	156/345.43
*	M	US-2004/0129211 A1	07-2004	Blonigan et al.	118/715

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0061445 A1	03-2005	Koshiishi et al.	156/345.47
*	B	US-2005/0098106 A1	05-2005	Fink et al.	118/715
*	C	US-2005/0150456 A1	07-2005	Senzaki et al.	118/715
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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